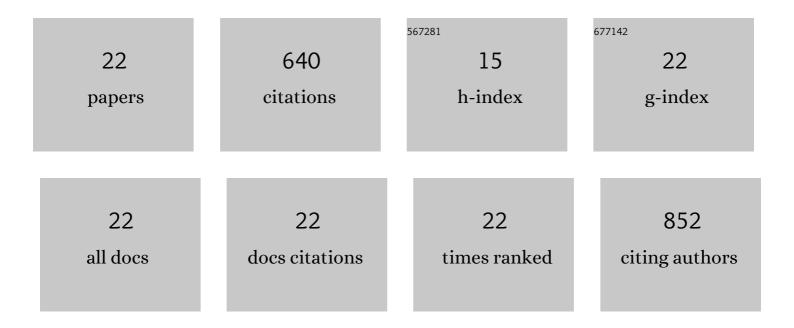
John Myers

List of Publications by Year in descending order

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IOHN MYERS

#	Article	IF	CITATIONS
1	Enhanced Radiosensitization of Gold Nanospikes via Hyperthermia in Combined Cancer Radiation and Photothermal Therapy. ACS Applied Materials & Interfaces, 2016, 8, 28480-28494.	8.0	124
2	One‣tep Synthesis of Superbright Water‣oluble Silicon Nanoparticles with Photoluminescence Quantum Yield Exceeding 80%. Advanced Materials Interfaces, 2015, 2, 1500360.	3.7	107
3	Elucidation of molecular structures at buried polymer interfaces and biological interfaces using sum frequency generation vibrational spectroscopy. Soft Matter, 2013, 9, 4738.	2.7	78
4	Molecular Ordering of Phenyl Groups at the Buried Polystyrene/Metal Interface. Langmuir, 2014, 30, 9418-9422.	3.5	35
5	Hygrothermal Aging Effects on Buried Molecular Structures at Epoxy Interfaces. Langmuir, 2014, 30, 165-171.	3.5	34
6	Controlled Drug Release and Hydrolysis Mechanism of Polymer–Magnetic Nanoparticle Composite. ACS Applied Materials & Interfaces, 2015, 7, 9410-9419.	8.0	33
7	Molecular Behavior at Buried Epoxy/Poly(ethylene terephthalate) Interface. Langmuir, 2014, 30, 12541-12550.	3.5	25
8	Surface plasma treatment effects on the molecular structure at polyimide/air and buried polyimide/epoxy interfaces. Chinese Chemical Letters, 2015, 26, 449-454.	9.0	24
9	In Situ Observation of Water Behavior at the Surface and Buried Interface of a Low-K Dielectric Film. ACS Applied Materials & Interfaces, 2014, 6, 18951-18961.	8.0	23
10	Interfacial Fresnel Coefficients and Molecular Structures of Model Cell Membranes: From a Lipid Monolayer to a Lipid Bilayer. Journal of Physical Chemistry C, 2014, 118, 28631-28639.	3.1	20
11	Nondestructive in Situ Characterization of Molecular Structures at the Surface and Buried Interface of Silicon-Supported Low- <i>k</i> Dielectric Films. Journal of Physical Chemistry B, 2015, 119, 1736-1746.	2.6	20
12	Polymer molecular behaviors at buried polymer/metal and polymer/polymer interfaces and their relations to adhesion in packaging. Journal of Adhesion, 2017, 93, 1081-1103.	3.0	19
13	Characterization of polymer/epoxy buried interfaces with silane adhesion promoters before and after hygrothermal aging for the elucidation of molecular level details relevant to adhesion. RSC Advances, 2015, 5, 105622-105631.	3.6	18
14	Influence of casting solvent on phenyl ordering at the surface of spin cast polymer thin films. Journal of Colloid and Interface Science, 2014, 423, 60-66.	9.4	16
15	Nondestructive Characterization of Molecular Structures at Buried Copper/Epoxy Interfaces and Their Relationship to Locus of Failure Analysis. IEEE Transactions on Components, Packaging and Manufacturing Technology, 2015, 5, 1432-1440.	2.5	15
16	Room temperature freezing and orientational control of surface-immobilized peptides in air. Chemical Communications, 2015, 51, 11015-11018.	4.1	12
17	SFG analysis of the molecular structures at the surfaces and buried interfaces of PECVD ultralow-dielectric constant pSiCOH. Journal of Applied Physics, 2016, 119, .	2.5	9
18	Plasma Treatment Effects on Molecular Structures at Dense and Porous Low- <i>k</i> SiCOH Film Surfaces and Buried Interfaces. Journal of Physical Chemistry C, 2015, 119, 22514-22525.	3.1	8

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#	Article	IF	CITATIONS
19	Distinct Molecular Structures of Edge and Middle Positions of Plasma Treated Covered Polymer Film Surfaces Relevant in the Microelectronics Industry. IEEE Transactions on Components, Packaging and Manufacturing Technology, 2017, 7, 1377-1390.	2.5	8
20	SFG analysis of the molecular structures at the surfaces and buried interfaces of PECVD ultralow-dielectric constant pSiCOH: Reactive ion etching and dielectric recovery. Applied Physics Letters, 2017, 110, .	3.3	5
21	Probing the molecular structures of plasma-damaged and surface-repaired low-k dielectrics. Physical Chemistry Chemical Physics, 2015, 17, 26130-26139.	2.8	4
22	Silicon Nanoparticles: Oneâ€Step Synthesis of Superbright Waterâ€Soluble Silicon Nanoparticles with Photoluminescence Quantum Yield Exceeding 80% (Adv. Mater. Interfaces 16/2015). Advanced Materials Interfaces, 2015, 2, .	3.7	3